

ABSTRACT

To attain an object of providing an insert for

5 holding wide-ranging kinds of area array type electronic components and realizing certain connection between external terminals of an area array type electronic component and connection terminals of a socket, and an electronic component testing apparatus and an electronic

10 component testing method using the same, a thin plate 163 for supporting an IC device 2 is positioned between an external terminal face 23 of the IC device 2 and a connection terminal face 42 of a socket 40, and a thickness of the thin plate 163 is made to be

15 approximately equal to or less than a distance between a tip portion of the external terminals 22 and the external terminal face 23.